

### 8Kx8 Static RAM CMOS, Low Power Monolithic

PRELIMINARY

The EDI8810H/L is a 65,653bit, 6 transistor cell CMOS Static RAM organized as 8Kx8.

It is available in both standard (H) and low power (L) versions. Both versions offer battery back-up data retention capability at VDD equal to 2V and 3V.

In addition to 13 address inputs, and 8 common data inputs and outputs, the device contains 4 control lines. The  $\bar{E}1$  and E2 lines perform chip enable functions and automatically power-down the device when proper logic levels are applied. The  $\bar{G}$  and W lines facilitate read and write operations.

All inputs and outputs are TTL compatible and operate from a single 5V supply.

Military product compliant to MIL-STD-883, Paragraph 1.2.1 is available.

### Features

8Kx8 bit CMOS Static Random Access Memory

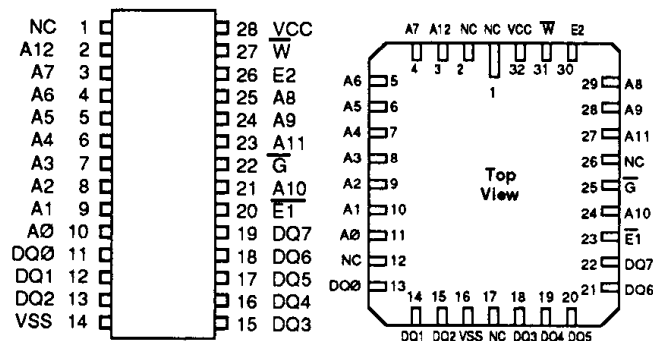
- Access Times 55 through 150ns
- $\bar{E}$  and  $\bar{G}$  Functions for Bus Control
- Data Retention Function
- TTL Compatible Inputs and Outputs

Jedec Approved Pinouts

- 28 Pin CERDIP, 600 mils wide, No. 70
- 32 Pad Ceramic LCC, No. 12

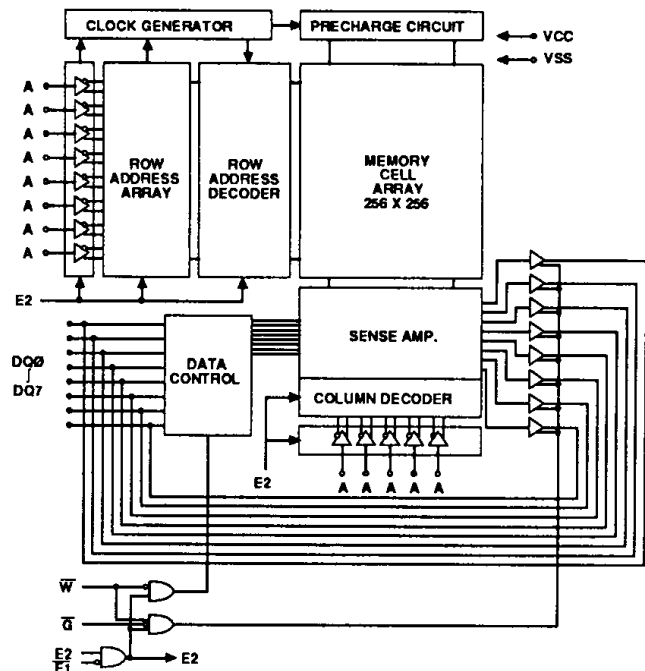
Single +5V ( $\pm 10\%$ ) Supply Operation

### Pin Configurations and Block Diagram



### Pin Names

A0-A12	Address Inputs
$\bar{E}1, E2$	Chip Enables
W	Write Enable
G	Output Enable
DQ0-DQ7	Common Data Input/Output
VCC	Power (+5V $\pm 10\%$ )
VSS	Ground
NC	No Connection



### Absolute Maximum Ratings\*

Voltage on any pin relative to VSS .....	-0.5V to 8.0V
Operating Temperature TA (Ambient)	
Industrial .....	-40°C to +85°C
Military .....	-55°C to +125°C
Storage Temperature, Ceramic. ....	-65°C to +150°C
Power Dissipation .....	1 Watt
Output Current. ....	20 mA
Junction Temperature, TJ .....	175°C

\*Stress greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions greater than those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

### Recommended DC Operating Conditions

Parameter	Sym	Min	Typ	Max	Units
Supply Voltage	VCC	4.5	5.0	5.5	V
Supply Voltage	VSS	0	0	0	V
Input High Voltage	VIH	2.2	--	6.0	V
Input Low Voltage	VIL	-0.5	--	0.8	V

### AC Test Conditions

Input Pulse Levels .....	VSS to 3.0V
Input Rise and Fall Times .....	5ns
Input and Output Timing Levels .....	1.5V
Output Load.: .....	1TTL, CL = 100pF

(note: For TEHQZ, TGHQZ and TWLQZ, CL = 5pF)

### DC Electrical Characteristics

Parameter	Sym	Conditions	Min	Typ*	Max	Units	
Operating Power Supply Current	ICC1	$\overline{W}, \overline{E1} = VIL, I/O = 0mA, \text{Min Cycle}; E2 = VIH$	--	45	70	mA	
Standby (TTL) Power Supply Current	ICC2	$\overline{E1} \geq VIH \text{ or } E2 \leq VIL$	--	--	2	mA	
Full Standby Power Supply Current	ICC3	$\overline{E1} \geq VCC-0.2V \text{ or } E2 \leq 0.2V$	H	--	1	500	$\mu A$
		$VIN \geq VCC-0.2V \text{ or } VIN \leq 0.2V$	L	--	0.2	100	$\mu A$
Input Leakage Current	ILI	$VIN = 0V \text{ to } VCC$	--	--	$\pm 5$	$\mu A$	
Output Leakage Current	ILO	$V I/O = 0V \text{ to } VCC$	--	--	$\pm 5$	$\mu A$	
Output High Voltage	VOH	$IOH = -1.0mA$	2.4	--	--	V	
Output Low Voltage	VOL	$IOL = 4.0mA$	--	--	0.4	V	

\*Typical = TA = 25°C, VCC = 5.0V

### Truth Table

$\overline{G}$	$\overline{E1}$	E2	$\overline{W}$	Mode	Output	Power
X	H	X	X	Standby	High Z	ICC2, ICC3
X	X	L	X	Standby	High Z	ICC2, ICC3
H	L	H	H	Output Deselect	High Z	ICC1
L	L	H	H	Read	DOUT	ICC1
X	L	H	L	Write	DIN	ICC1

### Capacitance

(f=1.0MHz, VIN=VCC or VSS)

Parameter	Sym	Max		Unit
		LCC	DIP	
Input Capacitance (Except DQ Pins)	CI	6	10	pF
Capacitance Control (DQ Pins)	CD/Q	8	12	pF

These parameters are sampled, not 100% tested.

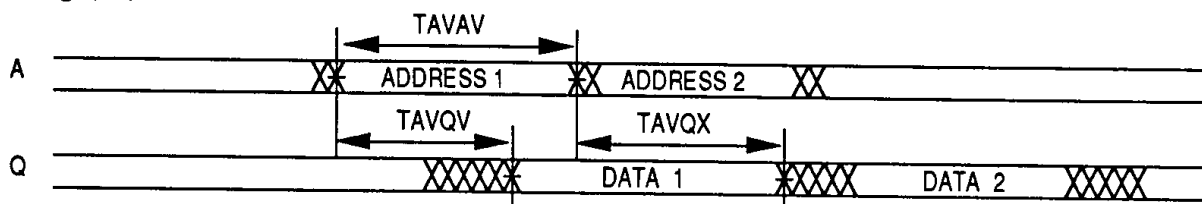
## AC Characteristics

### Read Cycle

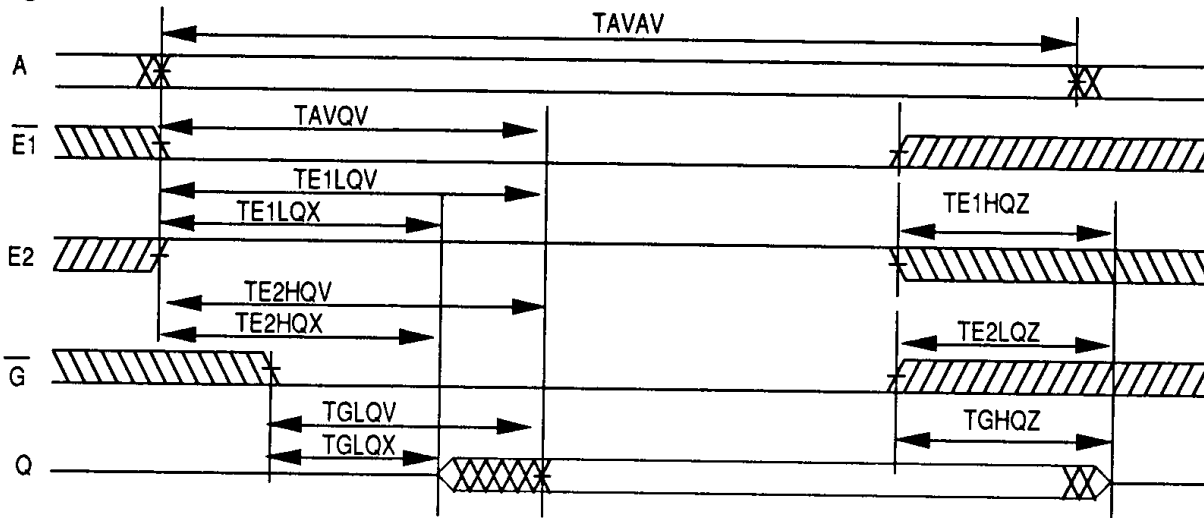
Parameter	Symbol	55ns		70ns		85ns		100ns		120ns		150ns		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Read Cycle Time	TAVAV	55		70		85		100		120		150		ns
Address Access Time	TAVQV		55		70		85		100		120		150	ns
Chip Enable Access Time	TE1LQV		55		70		85		100		120		150	ns
	TE2HQV		55		70		85		100		120		150	ns
Chip Enable to Output in Low Z (1)	TE1LQX	5		5		5		10		10		10		ns
	TE2HQX	5		5		5		10		10		10		ns
Output Enable to Output Valid	TGLQV		25		35		45		45		50		50	ns
Output Enable to Output in Low Z (1)	TGLQX	0		0		0		0		0		0		ns
Chip Disable to Output in High Z (1)	TE1HQZ	0	25	0	35	0	40	0	40	0	40	0	40	ns
	TE2LQZ	0	25	0	35	0	40	0	40	0	40	0	40	ns
Output Disable to Output in High Z (1)	TGHQZ		30		35		40		40		40		40	ns
Output Hold from Address Change	TAVQX	10		10		10		10		10		10		ns

Note 1: Parameter guaranteed, but not tested.

### Read Cycle 1 W, E2 High; G, E1 Controlled



### Read Cycle 2 W High

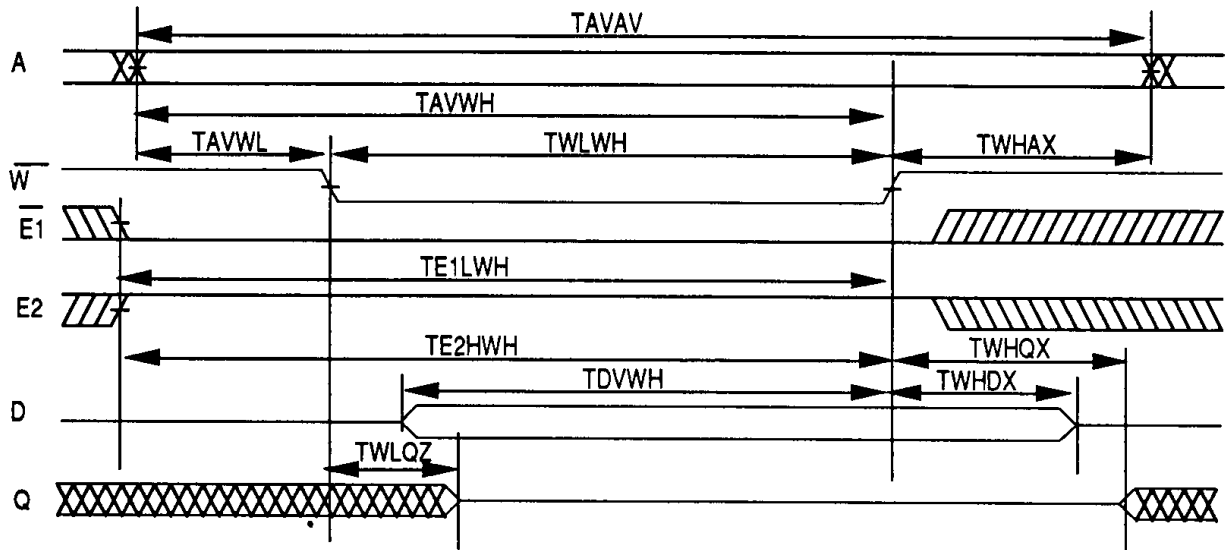


**AC Characteristics**  
**Write Cycle**

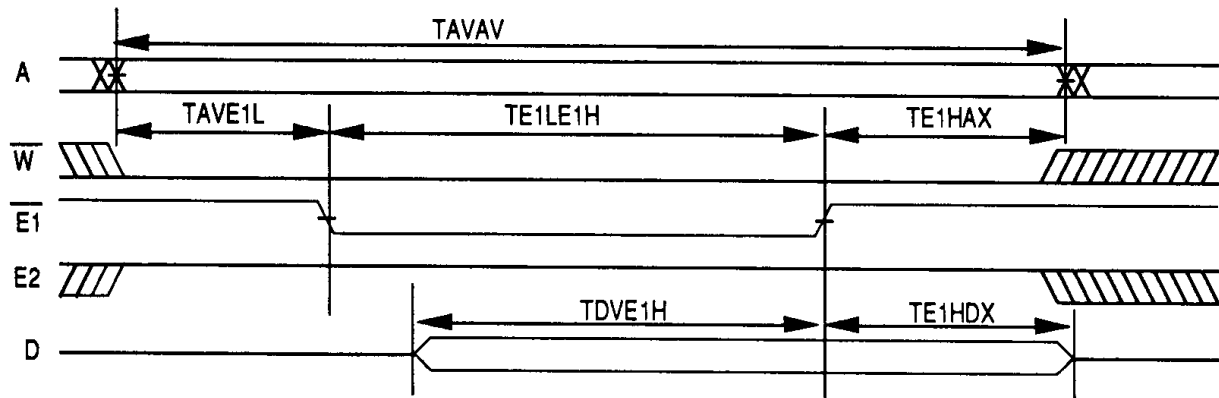
Parameter	Symbol		55ns		70ns		85ns		100ns		120ns		150ns		Unit
			Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Write Cycle Time	TAVAV		55		70		85		100		120		150		ns
Chip Enable to	TE1LWH	$\overline{E1}$	40		50		65		65		65		65		ns
End of Write	TE2HWH	E2	40		50		65		65		65		65		ns
Address Setup Time	TAVWL	$\overline{W}$	0		0		0		0		0		0		ns
	TAVE1L	$\overline{E1}$	0		0		0		0		0		0		ns
	TAVE2H	E2	0		0		0		0		0		0		ns
Address Valid to															
End of Write	TAVWH		40		50		65		65		65		65		ns
Write Pulse Width	TWLWH	$\overline{W}$	35		40		45		45		45		45		ns
	TE1LE1H	$\overline{E1}$	35		40		45		45		45		45		ns
	TE2HE2L	E2	35		40		45		45		45		45		ns
Write Recovery Time	TWHAX	$\overline{W}$	0		0		0		0		0		0		ns
	TE1HAX	E1	0		0		0		0		0		0		ns
	TE2LAX	E2	0		0		0		0		0		0		ns
Data Hold Time	TWHDX	$\overline{W}$	5		5		5		5		5		5		ns
	TE1HDX	$\overline{E1}$	5		5		5		5		5		5		ns
	TE2LDX	E2	5		5		5		5		5		5		ns
Write to Output															
in High Z (1)	TWLQZ			20		25		30		30		30		30	ns
Data to Write Time	TDVWH	$\overline{W}$	25		30		35		35		35		35		ns
	TDVE1H	$\overline{E1}$	25		30		35		35		35		35		ns
	TDVE2L	E2	25		30		35		35		35		35		ns
Output Active from															
End of Write (1)	TWHQX		5		5		5		5		5		5		ns

Note 1: Parameter guaranteed, but not tested.

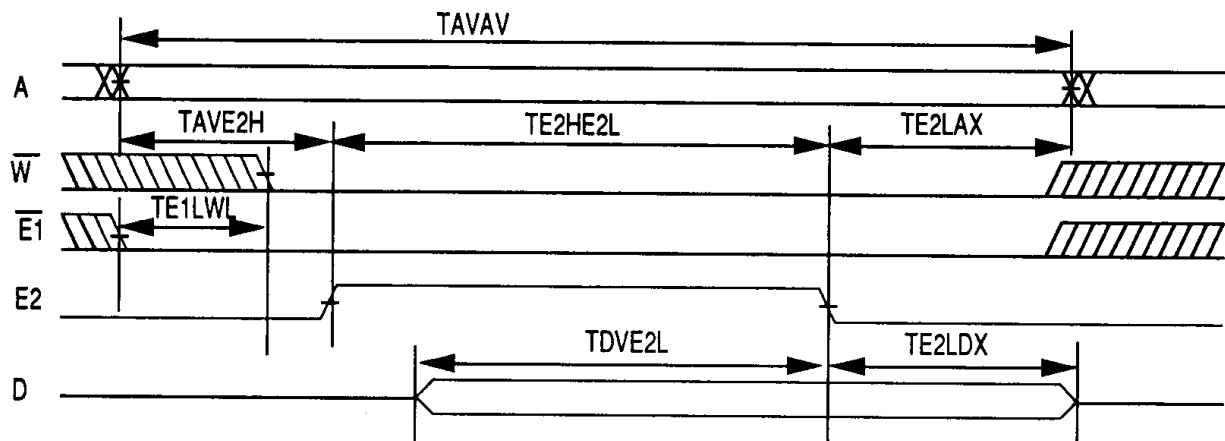
**Write Cycle 1  
Late Write,  $\overline{W}$  Controlled**



**Write Cycle 2  
Early Write,  $\overline{E1}$  Controlled**



**Write Cycle 3  
Early Write, E2 Controlled**

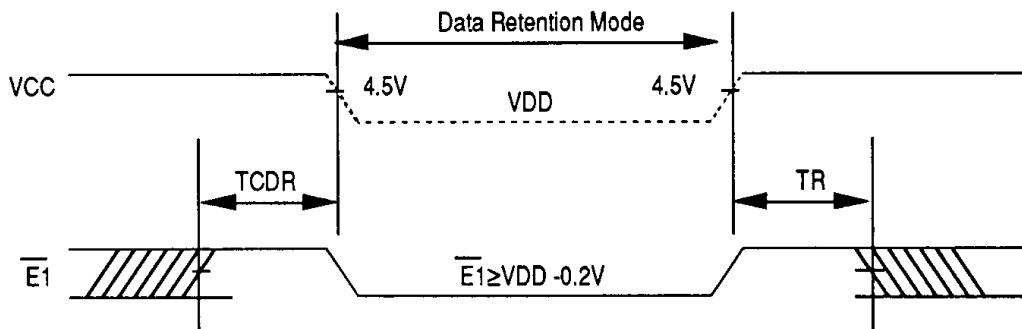


### Data Retention Characteristics

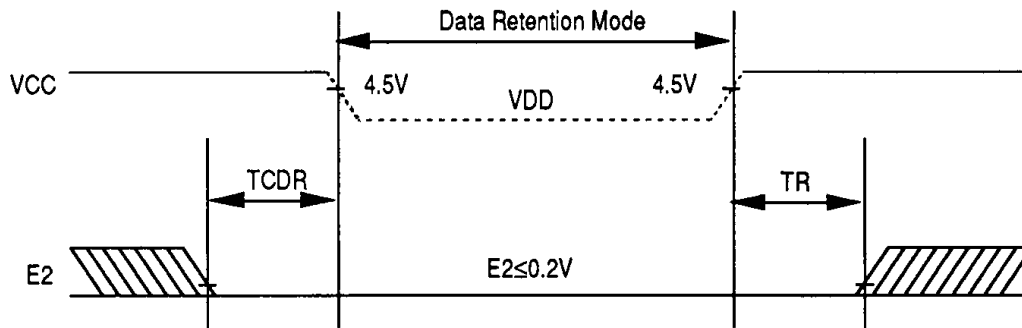
Characteristic	Sym	Test Conditions	VDD	Min	Typ	Max		Unit
						H	L	
Data Retention Voltage	VDD	$\overline{E1} \geq VDD - 0.2V$			2	--	--	V
Data Retention Quiescent Current	ICCDR	$E2 \leq 0.2V$ $VIN \geq VDD - 0.2V$	2V	--	0.1	200	50	$\mu A$
			3V	--	0.3	300	75	$\mu A$
Chip Disable to Data Retention Time	TCDR	or $VIN \leq 0.2V$		0	--	--	--	ns
Operation Recovery Time	TR			TAVAV*	--	--	--	ns

\*Read Cycle Time

#### Data Retention $\overline{E1}$ Controlled



#### Data Retention E2 Controlled



Since its founding in 1980, Electronic Designs, Incorporated has been a recognized innovator in the packaging of high-performance memory devices, and was the first supplier to provide memory products incorporating the space saving benefits of surface mount technology. EDI's commercial and military CMOS SRAM modules, assembled using surface mount techniques developed at EDI, continue to lead the industry in performance, density, quality and reliability.

Experience in surface mount assembly has led EDI to understand its customers' packaging needs. As a result, EDI provides its customers with high performance monolithic CMOS memory devices in a variety of package styles to suit both surface mount and thru-hole applications.

As chip size increases with megabit+ densities compliant leads become essential for surface mount bond integrity. EDI has taken a leadership role by proposing a J-leaded ce-

ramic package as the next generation standard for military surface mount applications.

This package also brings the military standard closer to the commercial, since the CSOJ offers the same footprint and pinout as the standard commercial device packaged in plastic SOJ. The additional benefit of adopting this standard is an inherent cost reduction in prototyping, handling and testing.

EDI's CSOJ package is included in the latest revision of DESC-SMD 5962-89598 for the 128Kx8 SRAM.

Because EDI recognizes that customer's needs vary, EDI's memory devices are offered in the widest variety of standard package options on the market today, as demonstrated by the 15 pages of package drawings included in this data book. The specific package drawing for each product listed in shown in the Product Selector Guide, the first page of each product specification, and listed by part number beginning on page 343.